

<b>Notice of References Cited</b>	Application/Control No. 09/344,826	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Stephen M. Brinich	Art Unit 2625	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,072,451	06-2000	Mano et al.	345/89
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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	N	JP 08044313 A	02-1996	Japan	DENDA et al.	
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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